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(37 CFR 1.98(b))	April 20, 2006	2814

## U.S. PATENT OR PUBLISHED U.S. PATENT APPLICATION DOCUMENTS

EXAMINER INITIAL	PATENT DOCUMENT	ISSUE/PUB DATE	PATENTEE	CLASS	SUB- CLASS	FILING DATE
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FOREIGN PATENT OR PUBLISHED FOREIGN PATENT APPLICATION

EXAMINER INITIAL	DOCUMENT NUMBER	PUBL. DATE	COUNTRY OR PATENT OFFICE	CLASS	SUB- CLASS	TRANSI YES	ATION NO
	WO9534504	12/21/95	PCT				

OTHER DOCUMENTS (Including Author, Title, Date, Place of publication)

	Kim, Hyun-Tak et al, "Gate Induced Mott Transition",5/27/03, New Journal of Physics		
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Examiner	/Long Pham/ (11/12/2007) DATE CONSIDERED		
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